CD74HC283, CD74HCT283

High Speed CMOS Logic 4-Bit Binary Full Adder with Fast Carry

Data sheet acquired from Harris Semiconductor
SCHS176

November 1997

Features

- **Adds Two Binary Numbers**
- **Full Internal Lookahead**
- **Fast Ripple Carry for Economical Expansion**
- **Operates with Both Positive and Negative Logic**
- **Fanout (Over Temperature Range)**
  - **Standard Outputs . . . . . 10 LSTTL Loads**
  - **Bus Driver Outputs . . . . . 15 LSTTL Loads**
- **Wide Operating Temperature Range . . . -55^{O}C to 125^{O}C**
- **Balanced Propagation Delay and Transition Times**
- **Significant Power Reduction Compared to LSTTL Logic ICs**
- **HC Types**
  - **2V to 6V Operation**
  - **High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V**
- **HCT Types**
  - **4.5V to 5.5V Operation**
  - **Direct LSTTL Input Logic Compatibility, V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)**
  - **CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL}, V_{OH}**

Description

The Harris CD74HC283 and CD74HCT283 binary full adders that add two 4-bit binary numbers and generate a carry-out bit if the sum exceeds 15.

Because of the symmetry of the add function, this device can be used with either all active-high operands (positive logic) or with all active-low operands (negative logic). When using positive logic the carry-in input must be tied low if there is no carry-in.

Ordering Information

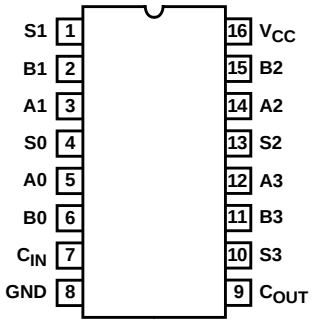
PART NUMBER	TEMP. RANGE (^{O}C)	PACKAGE	PKG. NO.
CD74HC283E	-55 to 125	16 Ld PDIP	E16.3
CD74HCT283E	-55 to 125	16 Ld PDIP	E16.3
CD74HC283M	-55 to 125	16 Ld SOIC	M16.15
CD74HCT283M	-55 to 125	16 Ld SOIC	M16.15

NOTES:

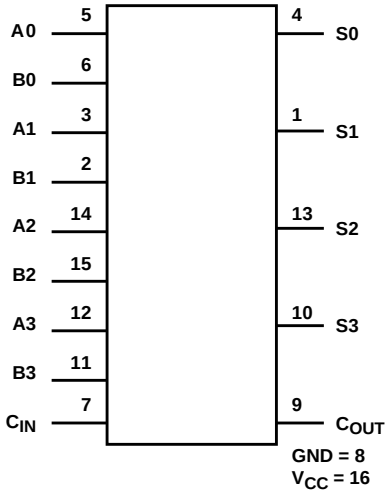
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Pinout

CD74HC283, CD74HCT283
(PDIP, SOIC)
TOP VIEW



Functional Diagram



Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . . -0.5V to 7V
DC Input Diode Current, I_{IK}
For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . . ±20mA
DC Drain Current, per Output, I_O
For -0.5V < V_O < V_{CC} + 0.5V. . . . . ±25mA
DC Output Source or Sink Current per Output Pin, I_O
For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . . ±25mA
DC V_{CC} or Ground Current, I_{CC} . . . . . ±50mA

Operating Conditions

Temperature Range, T_A . . . . . -55°C to 125°C
Supply Voltage Range, V_{CC}
HC Types . . . . . 2V to 6V
DC Input or Output Voltage, V_I, V_O . . . . . 0V to V_{CC}
Input Rise and Fall Time
2V . . . . . 1000ns (Max)
4.5V. . . . . 500ns (Max)
6V . . . . . 400ns (Max)

Thermal Information

Thermal Resistance (Typical, Note 3) θ_{JA} (°C/W)
PDIP Package 90
SOIC Package 160
Maximum Junction Temperature . . . . . 150°C
Maximum Storage Temperature Range . . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . . 300°C
(SOIC - Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS V_I (V)	TEST CONDITIONS I_O (mA)	V_{CC} (V)	25°C MIN	25°C TYP	25°C MAX	-40°C TO 85°C MIN	-40°C TO 85°C MAX	-55°C TO 125°C MIN	-55°C TO 125°C MAX	UNITS
HC TYPES												
High Level Input Voltage	V_{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	V_{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V
			4	4.5	-	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	-	8	-	80	-	160	µA

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HCT Types												
High Level Input Voltage	V_{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V_{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V_{OH}	V_{IL} or V_{IH}	-	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads	V_{OH}	V_{IL} or V_{IH}	-	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	-	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads	V_{OL}	V_{IH} or V_{IL}	-	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} to GND	-	5.5	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	ICC	V_{CC} or GND	-	5.5	-	-	8	-	80	-	160	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load (Note 4)	ΔI_{CC}	V_{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	µA

NOTE:

4. For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
C_{IN}	1.5
B1, A1, A0	1
B0	0.4
B3, A3, A2, B2	0.5

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g., 360µA max at 25°C.

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay C_{IN} to S0	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	160	-	200	-	240	ns
			4.5	-	-	32	-	40	-	48	ns
		C_L = 15pF	5	-	13	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	27	-	34	-	41	ns

Switching Specifications Input t_r, t_f = 6ns **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
C_{IN} to S1	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	180	-	225	-	270	ns
			4.5	-	-	36	-	45	-	54	ns
		C_L = 15pF	5	-	15	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	31	-	38	-	46	ns
C_{IN} to S2, C_{IN} to C_{OUT}	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	195	-	245	-	295	ns
			4.5	-	-	39	-	49	-	59	ns
		C_L = 15pF	5	-	16	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	33	-	42	-	50	ns
C_{IN} to S3	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	230	-	290	-	345	ns
			4.5	-	-	46	-	58	-	69	ns
		C_L = 15pF	5	-	19	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	39	-	49	-	59	ns
An, Bn to C_{OUT}	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	195	-	245	-	295	ns
			4.5	-	-	39	-	49	-	59	ns
		C_L = 15pF	5	-	16	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	33	-	42	-	50	ns
An, Bn to Sn	t_{PLH}, t_{PHL}	C_L = 50pF	2	-	-	210	-	265	-	315	ns
			4.5	-	-	42	-	53	-	63	ns
		C_L = 15pF	5	-	18	-	-	-	-	-	ns
		C_L = 50pF	6	-	-	36	-	45	-	54	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	C_{IN}	C_L = 50pF	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance, (Notes 5, 6)	C_{PD}	-	5	-	70	-	-	-	-	-	pF
HCT TYPES											
Propagation Delay C_{IN} to S0	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	13	-	-	-	-	-	ns
		C_L = 50pF	4.5	-	-	31	-	39	-	47	ns
C_{IN} to S1	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	18	-	-	-	-	-	ns
		C_L = 50pF	4.5	-		43	-	54	-	65	ns
C_{IN} to S2, C_{IN} to C_{OUT}	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	19	-	-	-	-	-	ns
		C_L = 50pF	4.5	-		46	-	58	-	69	ns
C_{IN} to S3	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	22	-	-	-	-	-	ns
		C_L = 50pF	4.5	-		53	-	66	-	80	ns
An, Bn to C_{OUT}	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	20	-	-	-	-	-	ns
		C_L = 50pF	4.5	-		48	-	60	-	72	ns
An, Bn to Sn	t_{PLH}, t_{PHL}	C_L = 15pF	5	-	21	-	-	-	-	-	ns
		C_L = 50pF	4.5	-		49	-	61	-	74	ns
Output Transition Time	t_{TLH}, t_{THL}	C_L = 50pF	4.5	-		15	-	19	-	22	ns

Switching Specifications Input t_r, t_f = 6ns **(Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Input Capacitance	C_{IN}	-	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance, (Notes 5, 6)	C_{PD}	-	5	-	82	-	-	-	-	-	pF

NOTES:

5. C_{PD} is used to determine the dynamic power consumption, per package.
6. $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where: f_i = Input Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms

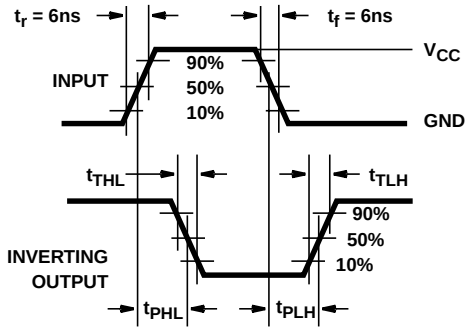


FIGURE 1. HC AND HCU TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

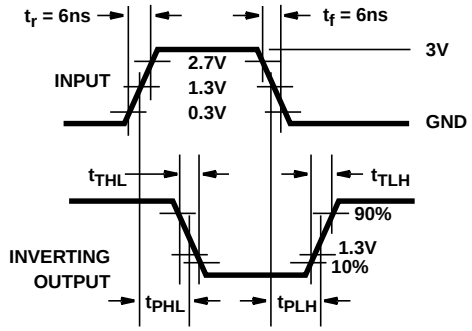


FIGURE 2. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

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